

**Search Notes**

Application/Control No.

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Examiner

Afsar M. Qureshi

Applicant(s)/Patent under  
Reexamination

KANG ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	230-231	11/8/2006	AQ
	335-338		
	345,442		
	395.53		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text, IEEE, NPL, JPO, EPO, DER	11/7/2006	AQ